

Hitachi S-4800

Ultra-high Resolution Scanning Electron Microscope (SEM)

Cold Field Emission Gun

acceleration voltages from 0.1 kV to 30 kV

max. resolution: 1.4 nm at 1 kV

1.0 nm at 15 kV

1.0 nm at 30 kV in STEM mode

Secondary Electron detector (upper / lower)

Transmitted Electron detector

EDX

QUANTAX 800 mit XFlash® 6 (Bruker)

recording spectra, element maps, line scans

